

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/754,227	WHITAKER ET AL.	
Examiner	Art Unit	
Jungwon Chang	2154	

SEARCHED				
Class	Subclass	Date	Examiner	
709	229 245	8/7/2005	JWC	
713	200	8/7/2005	JWC	
370	390 392	8/7/2005	JWC	
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*	According.			

INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)			
	DATE	EXMR	
East text ACM IEEE Search report attached	8/7/2005	JWC	